TOSHIBA Field Effect Transistor Silicon N Channel MOS Type (L^2 - π -MOSV)

2SK2312

Chopper Regulator, DC-DC Converter and Motor Drive Applications

• 4-V gate drive

• Low drain–source ON resistance : RDS (ON) = 13 m Ω (typ.)

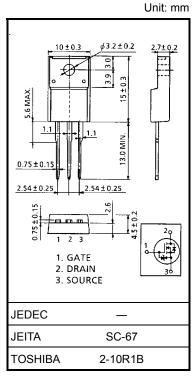
• High forward transfer admittance $: |Y_{fs}| = 40 \text{ S (typ.)}$

• Low leakage current : $I_{DSS} = 100 \mu A \text{ (max) (V}_{DS} = 60 \text{ V)}$

• Enhancement mode : $V_{th} = 0.8 \sim 2.0 \text{ V (V}_{DS} = 10 \text{ V, I}_{D} = 1 \text{ mA})$

Absolute Maximum Ratings (Ta = 25°C)

Characteri	stics	Symbol	Rating	Unit
Drain-source voltage		V_{DSS}	60	V
Drain-gate voltage (R	_{GS} = 20 kΩ)	V _{DGR}	60	V
Gate-source voltage		V _{GSS}	±20	V
Drain current	DC (Note 1)	I_{D}	45	Α
Diamiculient	Pulse (Note 1)	I_{DP}	180	Α
Drain power dissipation	n (Tc = 25°C)	P_{D}	45	W
Single pulse avalanche energy (Note 2)		E _{AS}	701	mJ
Avalanche current		I _{AR}	45	Α
Repetitive avalanche energy (Note 3)		E _{AR}	4.5	mJ
Channel temperature		T _{ch}	150	°C
Storage temperature range		T _{stg}	-55~150	°C



Weight: 1.9 g (typ.)

Note: Using continuously under heavy loads (e.g. the application of high temperature/current/voltage and the significant change in temperature, etc.) may cause this product to decrease in the reliability significantly even if the operating conditions (i.e. operating temperature/current/voltage, etc.) are within the absolute maximum ratings. Please design the appropriate reliability upon reviewing the Toshiba Semiconductor Reliability Handbook ("Handling Precautions"/Derating Concept and Methods) and individual reliability data (i.e. reliability test report and estimated failure rate, etc).

Thermal Characteristics

Characteristics	Symbol	Max	Unit
Thermal resistance, channel to case	R _{th (ch-c)}	2.78	°C/W
Thermal resistance, channel to ambient	R _{th (ch-a)}	62.5	°C/W

Note 1: Ensure that the channel temperature does not exceed 150°C.

Note 2: V_{DD} = 25 V, T_{ch} = 25 °C (initial), L = 471 μ H, R_{G} = 25 Ω , I_{AR} = 45 A

Note 3: Repetitive rating: pulse width limited by maximum channel temperature

This transistor is an electrostatic-sensitive device.

Please handle with caution.



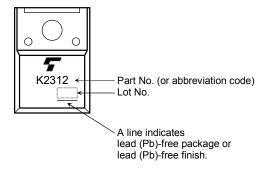
Electrical Characteristics (Ta = 25°C)

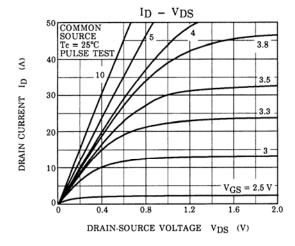
Charac	eteristics	Symbol	Test Condition	Min	Тур.	Max	Unit	
Gate leakage cu	rrent	I _{GSS}	V _{GS} = ±16 V, V _{DS} = 0 V	_	_	±10	μΑ	
Drain cut-off cu	rrent	I _{DSS}	V _{DS} = 60 V, V _{GS} = 0 V	_	_	100	μΑ	
Drain-source br	eakdown voltage	V (BR) DSS	I _D = 10 mA, V _{GS} = 0 V	60	_	_	V	
Gate threshold v	roltage	V _{th}	V _{DS} = 10 V, I _D = 1 mA	0.8	_	2.0	V	
Drain-source ON resistance		0	V _{GS} = 4 V, I _D = 25 A	_	19	25	m0	
Dialii-Source O	N resistance	R _{DS} (ON)	V _{GS} = 10 V, I _D = 25 A	_	13	17	mΩ	
Forward transfer	admittance	Y _{fs}	V _{DS} = 10 V, I _D = 25 A	28	40	_	S	
Input capacitano	e	C _{iss}		_	3350	_		
Reverse transfer capacitance		C _{rss}	V _{DS} = 10 V, V _{GS} = 0 V, f = 1 MHz	_	550	_	pF	
Output capacitance		C _{oss}		_	1600	_		
Switching time	Rise time	t _r	V _{GS} _{0V}	_	25	_		
	Turn-on time	t _{on}		_	55	_	- ns	
	Fall time	t _f		_	60	_		
	Turn-off time	t _{off}	$V_{DD} = 30V$ Duty $\leq 1\%$, $t_w = 10 \mu s$	_	180	_		
Total gate charge (Gate-source plus gate-drain)		Qg	V _{DD} ≈ 48 V, V _{GS} = 10 V, I _D = 45 A		110	ı		
Gate-source charge		Q _{gs}			70	_	nC	
Gate-drain ("miller") charge		Q_{gd}			40	_		

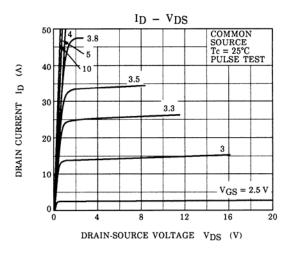
Source-Drain Ratings and Characteristics (Ta = 25°C)

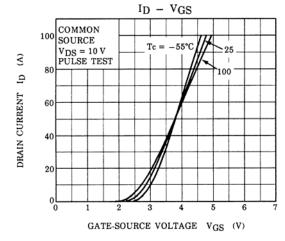
Characteristics	Symbol	Test Condition	Min	Тур.	Max	Unit
Continuous drain reverse current (Note 1)	I _{DR}	_	_	_	45	Α
Pulse drain reverse current (Note 1)	I _{DRP}	_	_	_	180	Α
Forward voltage (diode)	V_{DSF}	I _{DR} = 45 A, V _{GS} = 0 V	_	_	-1.7	V
Reverse recovery time	t _{rr}	I _{DR} = 45 A, V _{GS} = 0 V	_	120	_	ns
Reverse recovered charge	Q_{rr}	dl _{DR} / dt = 50 A / μs	_	0.2		μC

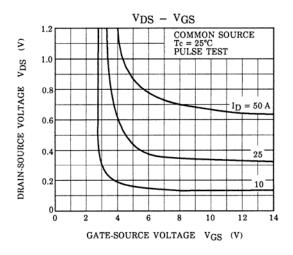
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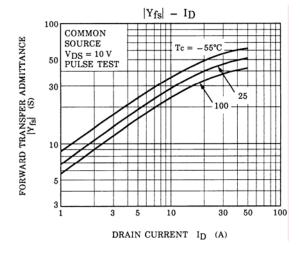


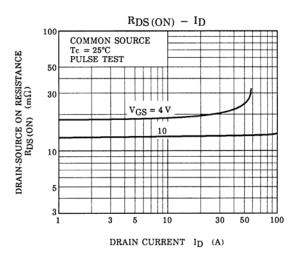


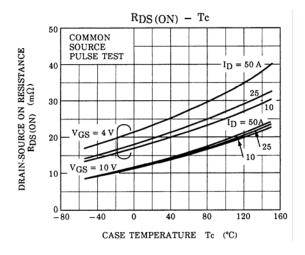


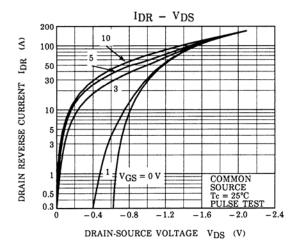


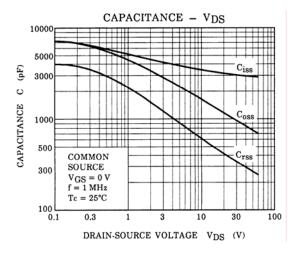


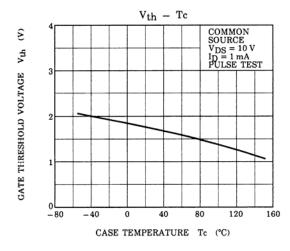


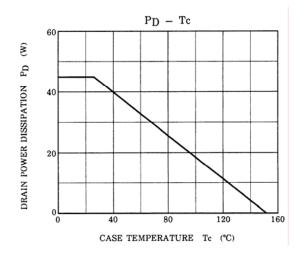


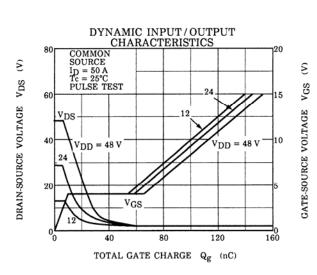




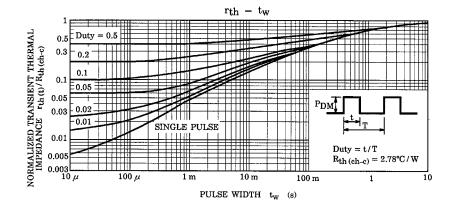


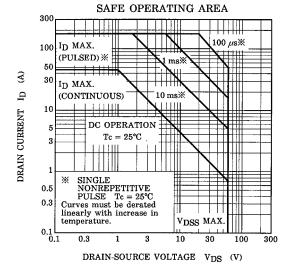


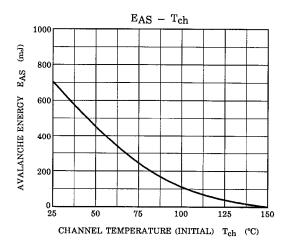


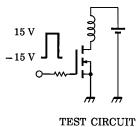


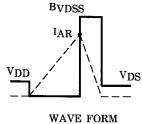
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$$R_G$$
 = 25 Ω
 V_{DD} = 25 V, L = 471 μH

$$EAS = \frac{1}{2} \cdot L \cdot I^{2} \cdot \left(\frac{BVDSS}{BVDSS - VDD} \right)$$

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